

00862.023537.

PATENT APPLICATION



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

where Application of:

JUN HIRABAYASHI ET AL.

Application No.: 10/826,315

Filed: April 19, 2004

For: EXPOSURE DECIDING METHOD

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: Examiner: Not Yet Assigned
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: Group Art Unit: 2852
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: March 30, 2006

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO-1449. Copies of the listed non-English documents are enclosed. Also, submitted with this disclosure is a Korean Office Action, citing the documents listed on the Form PTO-1449. The Korean Office Action was issued in a foreign counterpart application.

For the concise statement of relevance of non-English documents JPA 2001-309139 and JPA 10-181091, the Examiner's attention is directed to the attached English abstracts, and to the comment submitted by the Applicants, which state:

JPA 2001-309139 and JPA 10-181091 disclose fine-tuning the position of the pixel.

The feature of the present invention is to adjust exposure of each level in high accuracy so as to compensate difference of macroscopic density by displacement, and not fine-tune displacement occurred in accordance with conversion to low resolution to be printed by the engine.

For example, although the patterns e, f and g shown in Fig. 13 differ in the pixel position, the pattern and density are the same. However, when the patterns are converted to low resolution, the density differs in broad perspective as shown in the patterns e', f' and g'. The feature of the present invention is to adjust exposure in order to solve the problem that the density differs.

STATEMENT UNDER 37 C.F.R. § 1.97(e)

Each item of information in this information disclosure statement was first cited in any communication from a foreign Patent Office in a counterpart foreign application not more than three months prior to the filing date of this Statement.

CONCLUSION

It is respectfully requested that the above information be considered by the Examiner and that an initialed copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Applicants' undersigned attorney may be reached in our New York office by telephone at (212) 218-2100. All correspondence should continue to be directed to our address given below.

Respectfully submitted,


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U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)ATTY DOCKET NO.
00862.023537.APPLICATION NO.
10/826,315

APPLICANT

JUN HIRABAYASHI ET AL.

FILING DATE

April 19, 2004

GROUP

2852

U.S. PATENT DOCUMENTS

*EXAMINER
INITIALDOCUMENT
NUMBER

NAME

CLASS

SUBCLASS

FILING DATE
IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
/A.S./	JP	2001-309139	11/02/01	Japan			Abstract
/A.S./	JP	10-181091	07/07/98	Japan			Abstract

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER /Akwasi Sarpong/

DATE CONSIDERED

07/03/2008

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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